

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	2	shifting SAME stimulus SAME "pattern generator" SAME "compressed"	US-PGP UB	AND	ON	2006/03/16 09:11

Interference Search

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	64	"scan cell" SAME mask\$	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/03/16 07:37
L2	65	"output mask control\$"	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/03/16 07:37
L3	14	(G01R031/3185).ipc. AND mask\$	EPO; JPO; DERWE NT	AND	ON	2006/03/16 07:37
L4	380	(G01R031/3177 OR G01R031/3181).IPC.	EPO; JPO; DERWE NT	AND	ON	2006/03/16 07:37

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L5	3	(plural\$ NEAR3 compactors) SAME scan	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	OFF	2006/03/16 07:38
L6	39	plural\$ NEAR3 compactors	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	OFF	2006/03/16 07:38
L7	226	HDL AND RTL AND stimul\$ AND test respons\$	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/03/16 07:38
L8	908	(714/726).CCLS.	US-PGP UB; USPAT; USOCR	OR	OFF	2006/03/16 07:38

EAST Search History

L9	540	(714/727 OR 714/729).ccls.	US-PGP UB; USPAT; USOCR ; EPO; JPO; DERWE NT; IBM_T DB	AND	ON	2006/03/16 07:38
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#1	(((--scan cell-- same mask)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0
#2	(((scan cell same mask\$)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0
#3	(((scan cell same mask\$)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0
#4	(((scan test same mask\$)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0
#5	(((scan test same mask\$)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0
#6	(((scan same mask\$)<in>metadata)) <and> (pyr >= 2005 <and> pyr <= 2006)	0

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3	INZZ	scan ADJ cell SAME mask	unrestricted	0	-
4	INZZ	output ADJ mask ADJ control	unrestricted	0	-

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